Customer No. 31561 Attorney Docket No. 11514-US-PA Application No.: 10/710,637

IFU

IN THE UNIT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Applicant

: Chang

Application No. Filed

: 10/710,637 : 2004/7/27

For

: OVERLAY MARK AND METHOD OF FABRICATING

THE SAME

Examiner

: N/A

Art Unit

: 2812

## REQUEST FOR CORRECTING FILING RECEIPT

#### **VIA Courier**

ASSISTANT COMISSIONER FOR PATENTS Arlington, VA22202

Dear Sir:

A filing receipt for the above-identified application was received with thanks.

It is noted, however, that no data are printed under the item of Foreign Application in the filing receipt. Please be advised that the subject application purported to claim the priority benefit of Taiwan application serial no. 92127630, filed on October 6, 2003. However, this claim was not properly marked in the *e-pave* system, which may have led to the omission of the said priority data in the filing receipt for the subject application. Still, your attention is now kindly directed to two documents associated with the subject application in which this claim for the priority benefit of the said Taiwan application is believed duly made.

Firstly, in the combined declaration and power of attorney submitted concurrently with the filing of the subject application on July 27, 2004, Applicant has clearly indicated his intention to claim the priority benefit of the Taiwan application serial number 92127630. Further, in the filed specification for the subject application, the relation of the subject application and the said Taiwan application was disclosed in paragraph [0001] as well. A copy of the said combined declaration and power of attorney and the first page of the filed specification are attached herewith for your reference.

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**Application No.: 10/710,637** 

Applicant hereby respectfully solicits your formal recordation of the said priority

data and requests a corrected filing receipt reflecting the change in your record

concerning the subject application.

Enclosed please also find the following documents:

1. A copy of the filing receipt with the change noted thereon per request of the Office

2. A certified copy of the Taiwan Application No.: 92127630, filed on: 2003/10/6;

3. A prepaid return postcard.

I believe that no fee is incurred. However, the Commissioner is authorized to

charge any fees required in connection with the filing of this paper to account No.

50-2620 (Order No.: 11514-US-PA).

Thank you for your assistance in the subject matter. If you have any questions,

please feel free to contact me.

Respectfully Submitted,
JIANQ CHYUN Intellectual Property Office

Date: <u>Dec.</u> 6, 2004

V:

Belinda Lee

Registration No.: 46,863

Please send future correspondence to:

7F.-1, No. 100, Roosevelt Rd.,

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P920099 JC,3C1514-US-PA

the specification of which

## COMBINED DECLARATION AND POWER OF ATTORNEY

At the below named inventor, I hereby declare that:

believe I am an original, first and sole inventor (if only one name is listed below) or an original, first and joint inventor (if plural names are listed below) of the subject matter which is claimed and for which a patent is sought on the invention entitled

## OVERLAY MARK AND METHOD OF FABRICATING THE SAME

	X is attached her	eto.			
	was filed on _				
	as Application	Serial No.	and was amended on	•	
	I hereby state	that I have review	ved and understood the conter	nts of the abo	ve-identified
sp	pecification, includi	ng the claims, as an	nended by any amendment refer	red to above.	
	I acknowledge	the duty to disclos	e information which is material t	o the patental	oility of this
a	pplication in accord	dance with Title 37, (	Code of Federal Regulations, §	1.56(a).	
•	•		nefits under Title 35, United S	•	119 of any
fo	•	•	ntor's certificate listed below and		•
		•	ventor's certificate having a filir		
		·	iventor's certificate naving a filli	ig date belove	
•	•	priority is claimed:			
P	rior Foreign Applic	ation(s):			
	Number	Country	Date Filed(yyyy/mm/dd)	Yes	No
	92127630	Taiwan, R.O.C.	2003/10/06	X	

I hereby	appoint	the	following	attorney(s)	and/or	agent(s)	to	prosecute	this	application	and	to
transact all business in the Patent and Trademark Office connected therewith:												

Belinda Lee (Reg. No. 46,863) Charles Liu (Reg. No. 53,226)

**SEND CORRESPONDENCE TO:** 

DIRECT TELEPHONE CALLS TO:

(Name and Telephone Number)

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## COMBINED DECLARATION AND POWER OF ATTORNEY CONTINUED

I hereby declare that all statements made herein of my own knowledge are true and that all statements made on information and belief are believed to be true; and further that these statements were made with the knowledge that willful false statements and the like so made are punishable by fine or imprisonment, or both, under Section 1001 of Title 18 of the United States Code and that such willful false statements may jeopardize the validity of the application or any patents issued thereon.

Signature: Ching - Ufu Chang Date: 10-27 2003

Sole or First Joint Inventor: Ching-Yu Chang

Citizenship: Taiwan, R.O.C.

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Hsiang, Yilan Hsien, Taiwan, R.O.C.

**Electronic Version** 

Stylesheet Version v1.1.1



## Description

# [OVERLAY MARK AND METHOD OF FABRICATING THE SAME]

### **CROSS REFERENCE TO RELATED APPLICATIONS**

[0001] This application claims the priority benefit of Taiwan application serial no. 92127630, filed October 6, 2003.

#### **BACKGROUND OF INVENTION**

- [0002] Field of the Invention
- [0003] The invention relates to an overlay mark and a method of fabricating the same, capable of solving the problem of alignment measurement caused by low step height of the outer mark.
- [0004] Description of the Related Art
- [0005] In addition to the control of critical dimension (CD), factors for a successful photolithography process on a wafer include alignment accuracy (AA). Therefore, the measurement of accuracy, that is, the measurement of overlay error is crucial to the semiconductor fabrication process. An overlay mark is used as a tool for measuring overlay error and to determine whether the photoresist pattern is precisely aligned with the previous wafer layer on a wafer after a photolithography process.
- [0006] Conventionally, the overlay marks are located on the corners of the edge of each chip to measure whether the photoresist pattern is aligned with the previous wafer layer in the fabrication process.
- Figures 1A to 1C are cross sectional views illustrating a method of fabricating a metal interconnect having a via (via 0) and an overlay mark. Referring to Figure 1, a substrate 100 is provided, wherein the substrate 100 includes a chip region 102 and an overlay mark region 104. The dielectric layer 106a is formed on the substrate 100, and then the dielectric layer 106a is patterned to form a contact hole 108 in the

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**ART UNIT** 

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UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address COMMISSIONER FOR PATENTS
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Alexandria, Virginia 22313-1450 www.uspto.gov

DRAWINGS TOT CLMS IND CLMS

31561 JIANQ CHYUN INTELLECTUAL PROPERTY OFFICE 7 FLOOR-1, NO. 100 ROOSEVELT ROAD, SECTION 2 TAIPEI, 100 TAIWAN

(c) DATE

07/27/2004

10/710,637

**CONFIRMATION NO. 4636** 

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FILING RECEIPT

ATTY.DOCKET NO

11514-US-PA

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\*OC00000013746043\*

Date Mailed: 09/08/2004

Receipt is acknowledged of this regular Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Filing Receipt Corrections, facsimile number 703-746-9195. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections life JC IP Group L.L.C.

Applicant(s)

Ching-Yu Chang, Yilan Hsien, TAIWAN;

Power of Attorney: The patent practitioners associated with Customer Number 31561.

Domestic Priority data as claimed by applicant

Foreign Applications

VTAIWAN 92127630 10/06/2003

If Required, Foreign Filing License Granted: 09/07/2004

The number of your priority application, to be used for filing abroad under the Paris Convention is,

**Projected Publication Date: 02/02/2006** 

Non-Publication Request: No

Early Publication Request: No

Title